

#### **Development of Durable High Temperature PEMFC MEA**

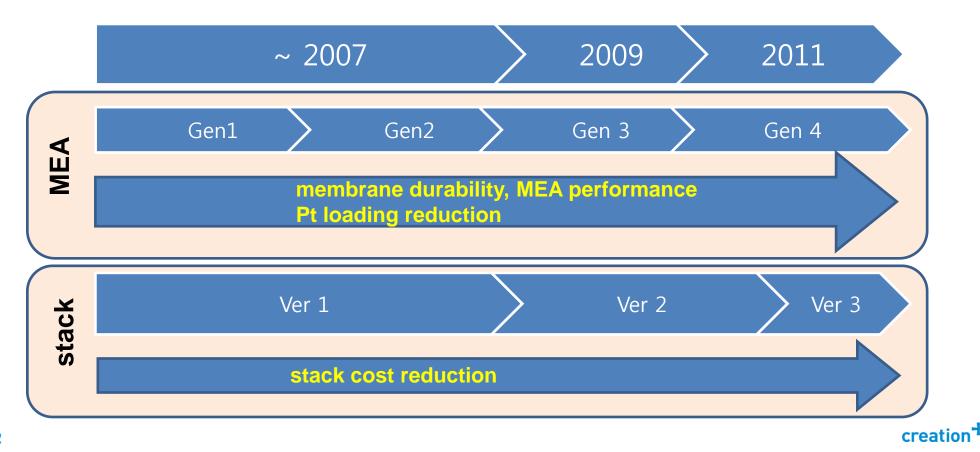


SAMSUNG ADVANCED INSTITUTE OF TECHNOLOGY (SAIT) SAMSUNG ELECTRONICS CO.

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# **Development of High Temperature PEMIFC MEA @SAIT**

- Development of membrane, MEA, stack and reformer for high temperature PEMFC
  - target : low cost and durable PEMFC system for residential applications
- Accumulation of membrane and MEA accelerated life time evaluation techniques
- High performance and durable high temperature MEA

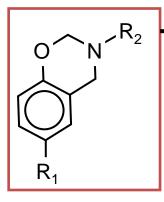


### **MEA Development Points**

- High performance
  - proton conductivity of membrane
  - electrode design
- Durability
  - membrane stability in acid and high temperature environment
  - oxidation resistant catalyst
- Cost reduction
  - Pt loading reduction
  - Manufacturing process simplification

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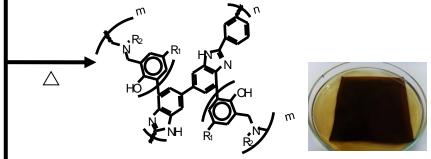
#### **Benzoxazine (BOA)**



#### Thermosetting Resin

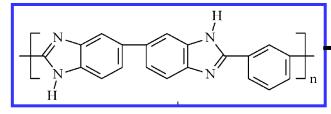
- Excellent mechanical properties
- High thermal stability
- No condensation product
- Low water uptake
- Molecular design flexibility
- Near zero shrinkage upon curing
- Low cost scale up production

#### grafted copolymer

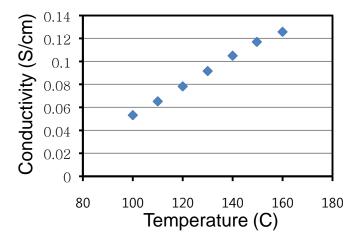


@160°C after 24h

#### Polybenzimidazole (PBI)



**Thermoplastic Polymer** 

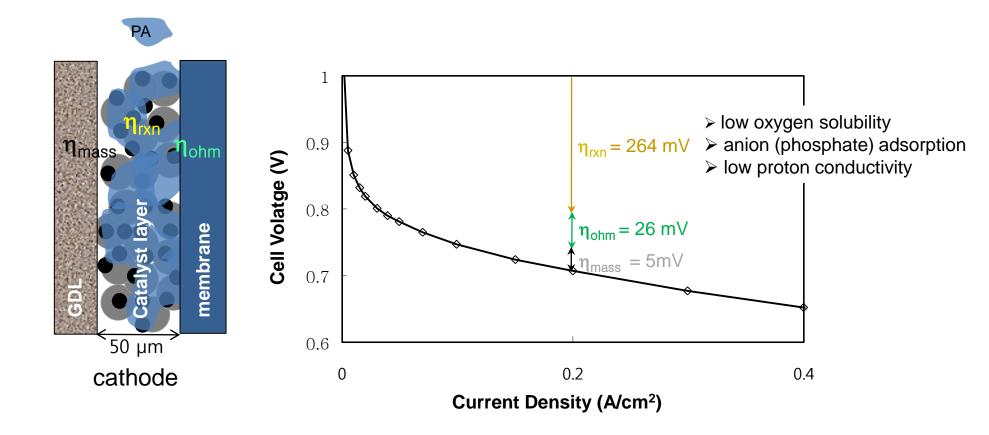




#### **MEA Performance Analysis**

Break down of overpotentials :  $\eta_{rxn} \gg \eta_{ohm} > \eta_{mass}$ ۲

Presence of phosphoric acid slows down ORR •

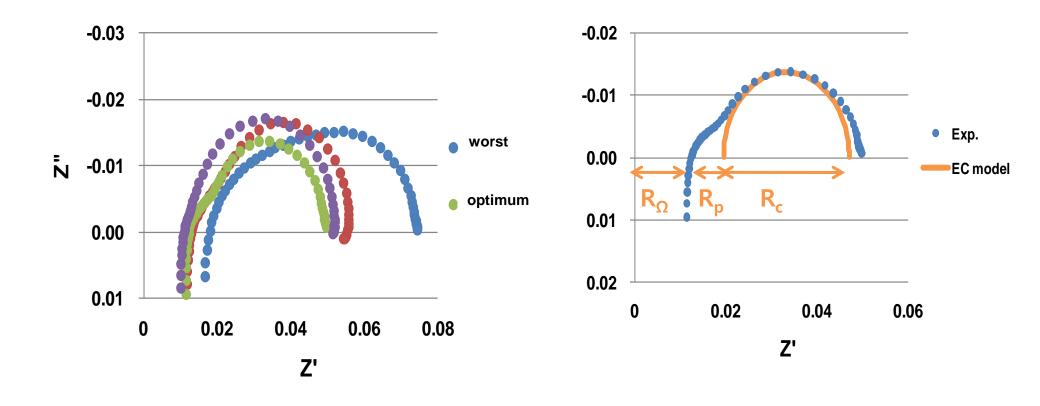


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### **Impedance Analysis**

- charge transfer resistance shape vary with acid distribution
- Separation of impedance into ohmic (R $_{\Omega}$ ), proton transfer (R $_p$ ) and charge transfer (R $_c$ ) resistance



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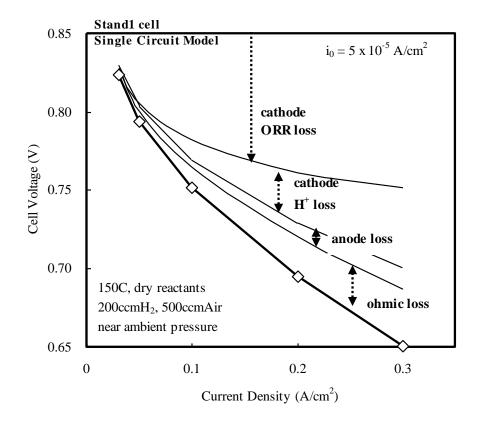
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#### **Impedance Analysis**

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- losses caused by ohmic, proton transfer, ORR resistances can be quantified.
- necessary improvements in the MEA can be proposed.

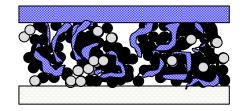


Impedance	Improvements
Ohmic	Conductivity of membrane Memb/catalyst layer interface
H <sup>+</sup> transfer	Acid distribution in catalyst layer
ORR	Catalyst improvement O <sub>2</sub> concentration in catalyst layer

more active Pt/C
non active Pt/C

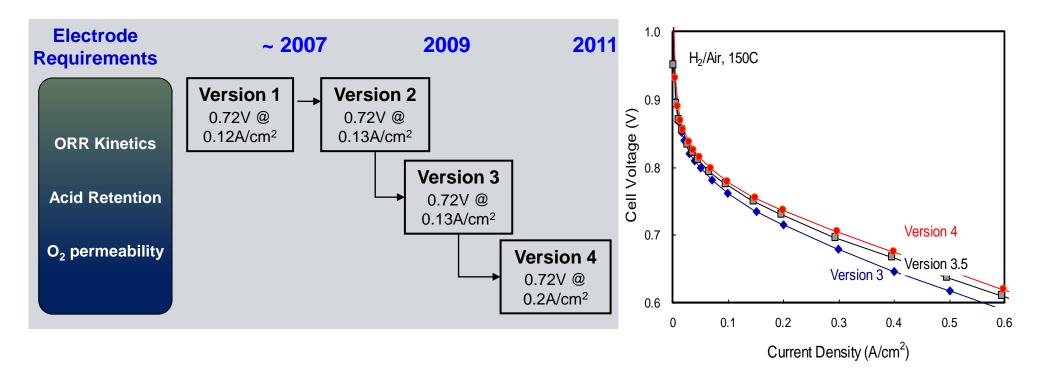
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#### **MEA Development**

- Improvements in cell voltage  $\rightarrow$  0.72 V @ 0.2 A/cm<sup>2</sup> (H<sub>2</sub>/air, 150 °C)
  - Implementing alloy catalyst and performance enhancing binder
  - Improving acid distribution and Pt utilization within MEA
- Cell performances analysis : *in-situ* electrochemical analysis and *ex-situ* methods

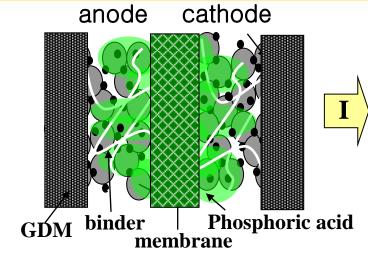


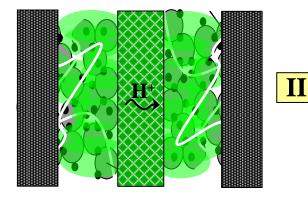
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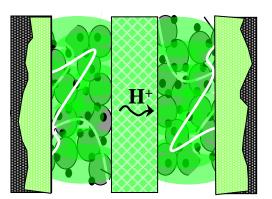
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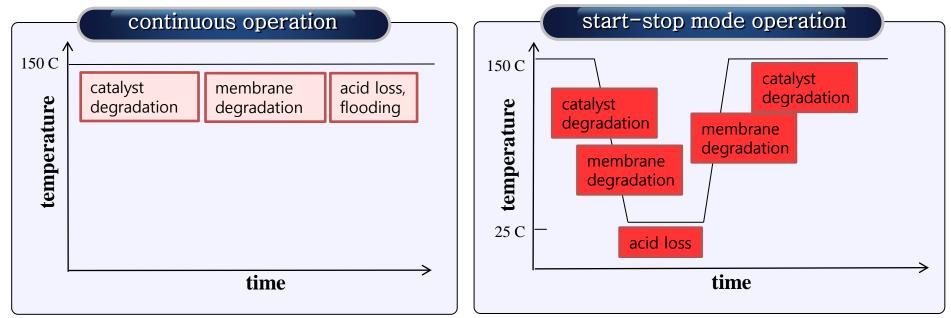
### Changes within MEA during operation

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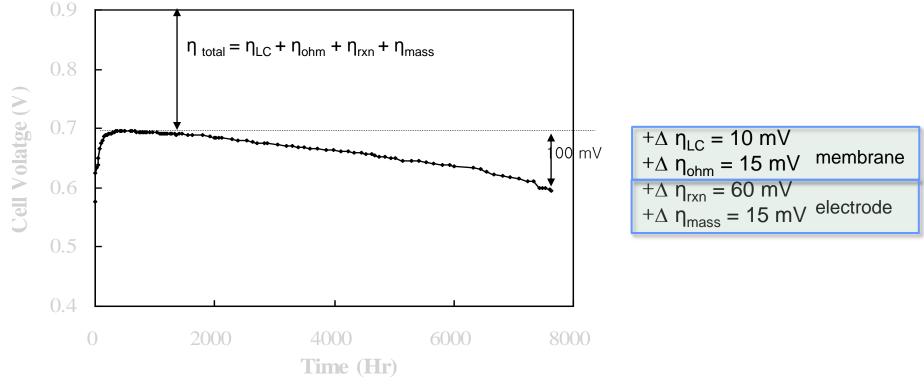




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### **MEA Durability Analysis**

- Changes of overpotentials during operation :  $\eta_{rxn} >> \eta_{ohm}$ ,  $\eta_{mass} > \eta_{LC}$
- Ex situ analysis of catalyst confirm degradation





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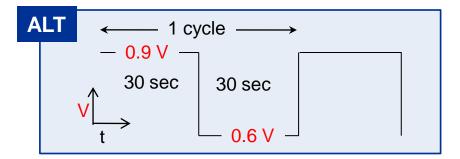
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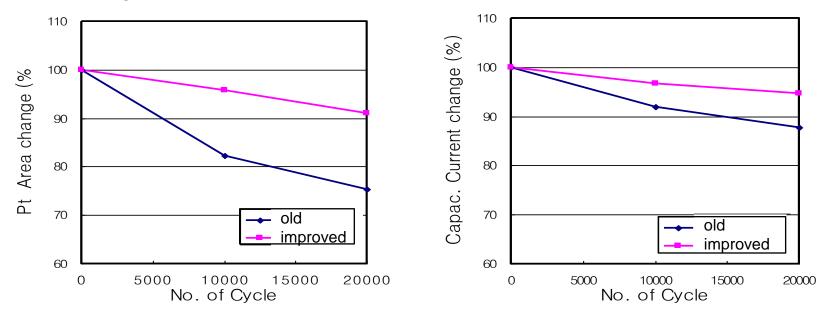
#### MEA Durability Improvement : Durable Catalyst () In advanced

- Catalyst screening : Accelerated Life Time test (ALT)
- Evaluation criteria :  $\Delta Pt_{S,A}$  and  $\Delta C_{S,A}$



Changes in Pt surface area



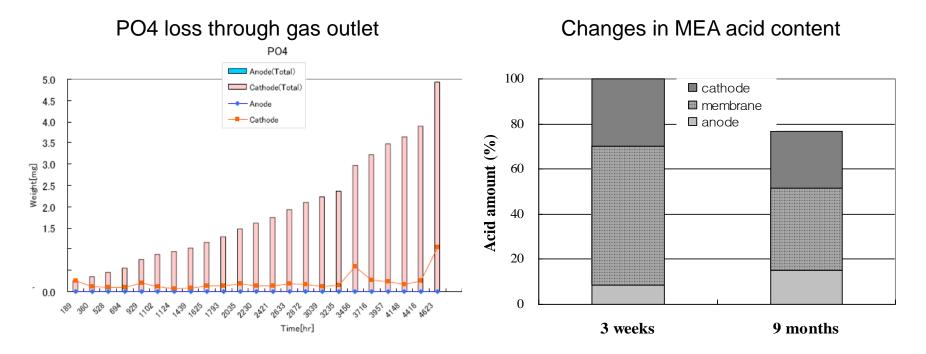




- Quantification of acid losses
  - during MEA operation : analysis of acid content in anode and cathode gas outlet

 $\rightarrow$  ~0.8 ug/hr (1.3 mg/cm<sup>2</sup> acid loss in 40,000 hr)

- after MEA operation : actual acid loss is larger.
- MEA optimization under progress

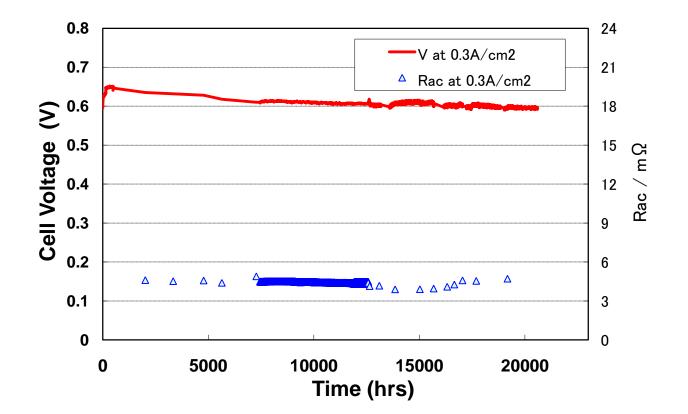


25 cm<sup>2</sup> cell, 150 °C, operated at 0.3A/cm<sup>2</sup> 0.66 ~ 0.95 µg/hr phosphoric acid loss

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#### **MEA Durability : Continuous Operation**

- Measured life time : 20,000 hrs, 2 uV/hr decay rate
- Improvements
  - mechanical property of membrane
  - oxidation resistance of catalyst



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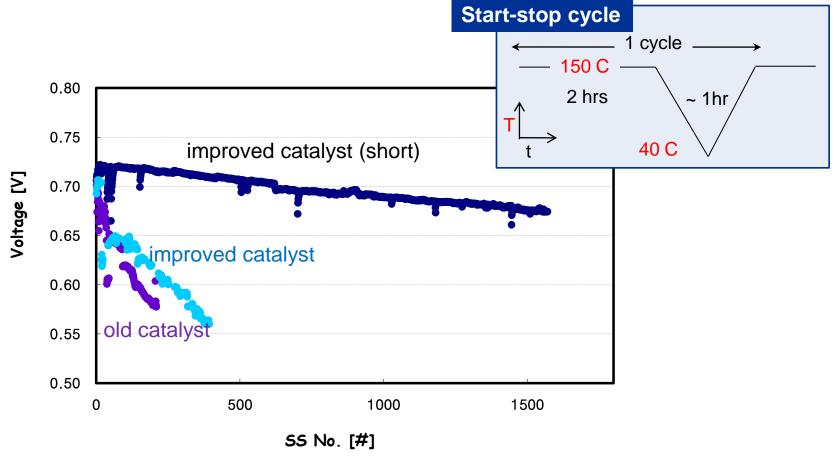
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25 cm<sup>2</sup> cell, 150 °C,  $H_2/air$ , operated at 0.3A/cm<sup>2</sup>

#### **MEA Durability : start-stop Operation**

- SS operation life time : 80% improvement
- By shorting the cell : > 1500 start-stop cycle



 $8\ cm^2$  cell, 150 °C, operated at 0.2A/cm^2



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# Conclusions

- Development of High temperature PEMFC at SAIT
  - High performance (0.72 V @ 0.2 A/cm<sup>2</sup>) and durable (20,000 hrs+) MEA
  - in-situ and ex-situ analysis techniques
  - ALT methods to screen membrane, catalyst and GDL materials
- Future Development Plans
  - Cost reduction by lowering Pt loading and using cost saving materials.
  - Simplification of MEA manufacturing processes
  - Verification of MEA performance at system level



### Acknowledgements

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# Thank you for your attention !



